## Notice of References Cited Application/Control No. 09/762,472 Examiner Li B. Zhen Applicant(s)/Patent Under Reexamination EDER ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-H0,001,918	11-2000	Hoffpauir et al.	379/242
	В	US-6,516,355 <sub>,</sub> B1	02-2003	Hartmann et al.	719/317
	С	US-6,119,187 A	09-2000	Hebert, Mark P.	710/105
	D	US-6,311,238 B1	10-2001	Hebert, Mark P.	710/65
	Ε	US-6,745,228 B2	06-2004	Riddle, Guy	709/204
	F	US-H0,001,895	10-2000	Hoffpauir et al.	455/433
	G	US-H0,001,897	10-2000	Fletcher et al.	455/433
	Н	US-H0,001,896	10-2000	Hoffpauir et al.	455/433
	ı	US-			
	J	US-	,		
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification	
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## **NON-PATENT DOCUMENTS**

	NON-I ATENT BOOGNENTO								
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